



#### 100V N-CHANNEL ENHANCEMENT MODE MOSFET

#### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub> T <sub>A</sub> = 25°C
100V	0.25Ω	1.9A

# **Description and Applications**

This MOSFET utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed, this makes it ideal for high efficiency power management applications.

- DC-DC Converters
- · Power management functions
- · Disconnect Switches
- Motor control

#### **Features and Benefits**

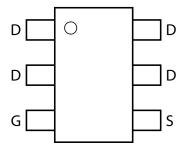
- · Low on-resistance
- · Fast switching speed
- Qualified to AEC-Q101 Standards for High Reliability

#### **Mechanical Data**

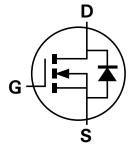
- Case: SOT23-6
- Case Material: Molded Plastic, UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Matte Tin Finish annealed over Copper leadframe.
   Solderable per MIL-STD-202, Method 208 63
- Weight: 0.015 grams (approximate)







Package Pin Out

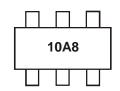


**Equivalent Circuit** 

#### **Ordering Information**

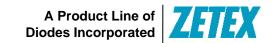
Product	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN10A08E6TA	7	8	3,000
ZXMN10A08E6TC	13	8	10,000

## **Marking Information**



10A8 = Product Type Marking Code





## **Maximum Ratings** @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source voltage			$V_{DSS}$	100	V
Gate-Source voltage			$V_{GS}$	±20	V
Continuous Drain current	V <sub>GS</sub> = 10V	(Note 2) T <sub>A</sub> = 70°C (Note 2) (Note 1)	I <sub>D</sub>	1.9 1.5 1.5	А
Pulsed Drain current (Note 3)		I <sub>DM</sub>	8.6	A	
Continuous Source current (Body diode) (Note 2)		Is	2.5	A	
Pulsed Source current (Body diode) (Note 3)		I <sub>SM</sub>	8.6	A	

#### **Thermal Characteristics**

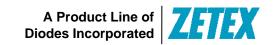
Characteristic		Symbol	Value	Unit
Power dissipation Linear derating factor	(Note 1)	D.	1.1 8.8	W mW/°C
Power dissipation Linear derating factor	(Note 2)	P <sub>D</sub>	1.7 13.6	W mW/°C
Thermal Resistance, Junction to ambient	ance, Junction to ambient (Note 1) (Note 2)		113 73	°C/W
Operating and storage temperature range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C

Notes:

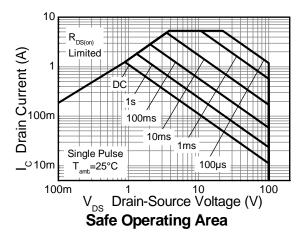
- 1. For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.
- 2. For a device surface mounted on FR4 PCB measured at t ≤ 5 sec.

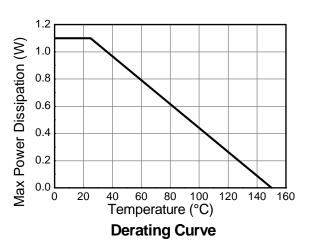
  3. Repetitive rating 25mm x 25mm FR4 PCB, D = 0.02, pulse current 300µs pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph

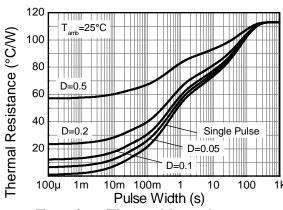


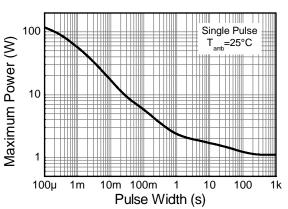


## **Thermal Characteristics**





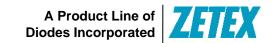




**Transient Thermal Impedance** 

**Pulse Power Dissipation** 





## Electrical Characteristics @TA = 25°C unless otherwise specified

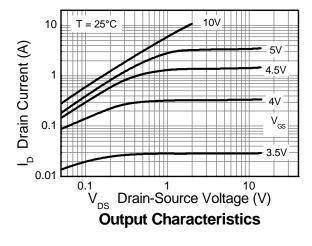
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	100	_	_	V	$I_D = 250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	0.5	μΑ	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	2	_	4	V	$I_D = 250 \mu A, V_{DS} = V_{GS}$	
Static Drain-Source On-Resistance (Note 4)	R <sub>DS (ON)</sub>	_	_	0.25 0.30	Ω	$V_{GS} = 10V, I_D = 3.2A$ $V_{GS} = 6V, I_D = 2.6A$	
Forward Transconductance (Notes 4 & 6)	g <sub>fs</sub>	_	5.0	_	S	$V_{DS} = 15V, I_D = 3.2A$	
Diode Forward Voltage (Note 4)	V <sub>SD</sub>	_	0.87	0.95	V	I <sub>S</sub> = 3.2A, V <sub>GS</sub> = 0V	
Reverse recovery time (Note 6)	t <sub>rr</sub>	_	27	_	ns	1 4 6 4 17/14 400 4 /	
Reverse recovery charge (Note 6)	Q <sub>rr</sub>	_	32		nC	I <sub>F</sub> = 1.2A, di/dt = 100A/μs	
DYNAMIC CHARACTERISTICS (Note 6)							
Input Capacitance	C <sub>iss</sub>	_	405		pF		
Output Capacitance	Coss	_	28.2	_	pF	$V_{DS} = 50V, V_{GS} = 0V$ - f = 1MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	14.2	_	pF	-1 = 11VII 12	
Total Gate Charge	Qg	_	4.2	_	nC	$V_{DS} = 50V, V_{GS} = 5V$ $I_{D} = 1.2A$	
Total Gate Charge	Qg	_	7.7	_	nC		
Gate-Source Charge	Q <sub>gs</sub>	_	1.8	_	nC	$V_{DS} = 50V, V_{GS} = 10V$	
Gate-Drain Charge	Q <sub>gd</sub>	_	2.1	_	nC	$I_D = 1.2A$	
Turn-On Delay Time (Note 5)	t <sub>D(on)</sub>	_	3.4	_	ns		
Turn-On Rise Time (Note 5)	t <sub>r</sub>	_	2.2		ns	$V_{DD} = 30V, V_{GS} = 10V$ $I_{D} = 1.2A, R_{G} \cong 6.0\Omega$	
Turn-Off Delay Time (Note 5)	t <sub>D(off)</sub>	_	8	_	ns		
Turn-Off Fall Time (Note 5)	t <sub>f</sub>	_	3.2	_	ns		

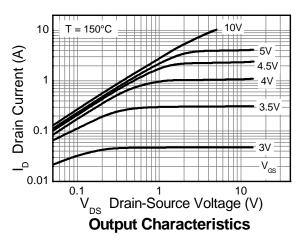
Notes:

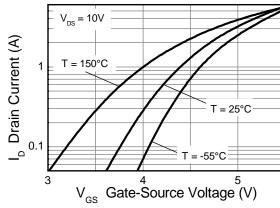
- 4. Measured under pulsed conditions. Pulse width  $\leq 300 \mu s;$  duty cycle  $\leq 2\%$
- 5. Switching characteristics are independent of operating junction temperatures.
- 6. For design aid only, not subject to production testing.

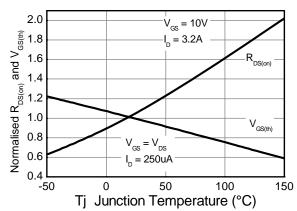


#### **Typical Characteristics**



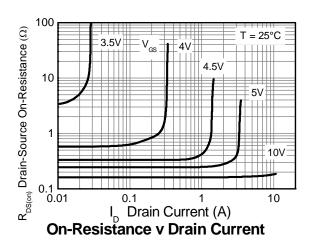


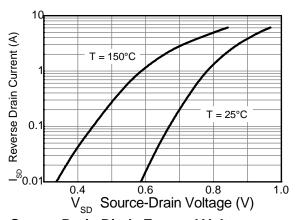




**Typical Transfer Characteristics** 

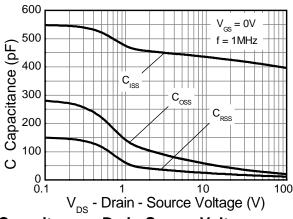


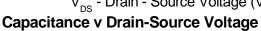


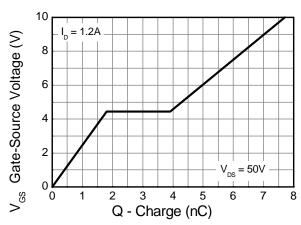




#### **Typical Characteristics - continued**

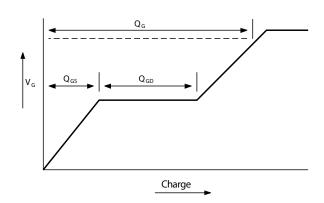




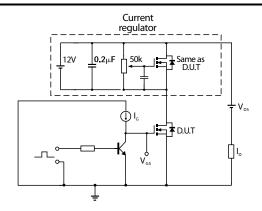


**Gate-Source Voltage v Gate Charge** 

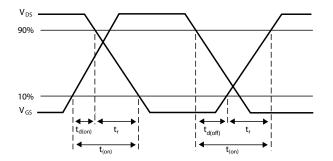
## **Test Circuits**



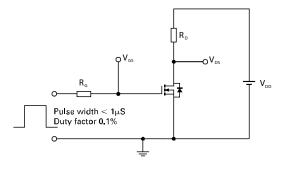
Basic gate charge waveform



Gate charge test circuit



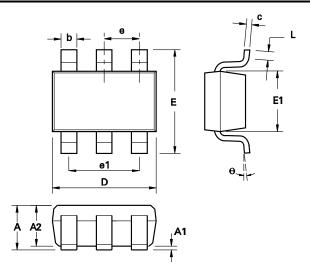
Switching time waveforms



Switching time test circuit

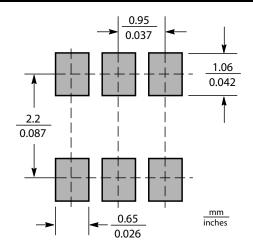


# **Package Outline Dimensions**



DIM	Millimeters		Inc	hes
	Min.	Max.	Min.	Max.
Α	0.90	1.45	0.35	0.057
A1	0.00	0.15	0	0.006
A2	0.90	1.30	0.035	0.051
b	0.35	0.50	0.014	0.019
С	0.09	0.20	0.0035	0.008
D	2.80	3.00	0.110	0.118
E	2.60	3.00	0.102	0.118
E1	1.50	1.75	0.059	0.069
L	0.10	0.60	0.004	0.002
е	0.95 REF		0.037 REF	
e1	1.90 REF		0.074 REF	
L	0°	10°	0°	10°

## **Suggested Pad Layout**







#### **IMPORTANT NOTICE**

DIODES INCORPORATED MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARDING TO THIS DOCUMENT, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION).

Diodes Incorporated and its subsidiaries reserve the right to make modifications, enhancements, improvements, corrections or other changes without further notice to this document and any product described herein. Diodes Incorporated does not assume any liability arising out of the application or use of this document or any product described herein; neither does Diodes Incorporated convey any license under its patent or trademark rights, nor the rights of others. Any Customer or user of this document or products described herein in such applications shall assume all risks of such use and will agree to hold Diodes Incorporated and all the companies whose products are represented on Diodes Incorporated website, harmless against all damages.

Diodes Incorporated does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel. Should Customers purchase or use Diodes Incorporated products for any unintended or unauthorized application, Customers shall indemnify and hold Diodes Incorporated and its representatives harmless against all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized application.

Products described herein may be covered by one or more United States, international or foreign patents pending. Product names and markings noted herein may also be covered by one or more United States, international or foreign trademarks.

#### LIFE SUPPORT

Diodes Incorporated products are specifically not authorized for use as critical components in life support devices or systems without the express written approval of the Chief Executive Officer of Diodes Incorporated. As used herein:

- A. Life support devices or systems are devices or systems which:
  - 1. are intended to implant into the body, or
  - 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
- B. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or to affect its safety or effectiveness.

Customers represent that they have all necessary expertise in the safety and regulatory ramifications of their life support devices or systems, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of Diodes Incorporated products in such safety-critical, life support devices or systems, notwithstanding any devices- or systems-related information or support that may be provided by Diodes Incorporated. Further, Customers must fully indemnify Diodes Incorporated and its representatives against any damages arising out of the use of Diodes Incorporated products in such safety-critical, life support devices or systems.

Copyright © 2009, Diodes Incorporated

www.diodes.com